19-4459; Rev 0; 2/09 EVALUATION KIT

AVAILABLE **Overvoltage Protection with USB Charger** Detection, LDO, and ESD Protection on D+/D-

General Description

The MAX14529E/MAX14530E are overvoltage-protection devices with USB charger detection, a low-dropout (LDO) regulator, and ESD protection. These devices feature a low $35m\Omega$ (typ) R_{ON} internal FET switch and protect low-voltage systems against voltage faults up to 28V. When the input voltage exceeds the overvoltage threshold, the internal FET switch is turned off to prevent damage to the protected components.

The charger detection detects a short between the USB D+ and D- data lines. If the data lines are shorted together and a dedicated charger is attached, the phone draws more than 500mA to charge the battery.

The overvoltage thresholds (OVLO) are preset to 5.75V (MAX14529E) or 6.8V (MAX14530E).

The LDO output (LOUT) is powered from OUT and supplies 3.3V to the USB transceiver. The LDO features a 100mA (min) current capability and low output noise.

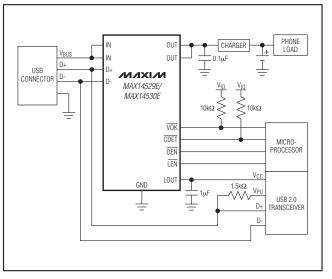
The MAX14529E/MAX14530E feature ±15kV HBM ESD protection with low (3pF) capacitance suitable for Hi-Speed USB 2.0.

Both devices are offered in a small 12-bump, 1.5mm x 2mm WLP package and operate over the -40°C to +85°C extended temperature range.

Applications

Cell Phones MP3 Players

PDAs and Palmtop Devices



Typical Operating Circuit

MIXI/M

Maxim Integrated Products 1

Features

K14529E/MAX14530E

- Input Voltage Protection Up to 28V
- High-Current USB Charger Detection
- 3.3V, 100mA LDO
- Preset Overvoltage Protection Trip Level 5.75V (MAX14529E) 6.8V (MAX14530E)
- Integrated Low Ron 35mΩ (typ) FET Switch
- Low-Capacitance USB High-Speed Data Line ESD Protection (3pF) ±15kV Human Body Model (HBM)
 - ±15kV IEC 61000-4-2 Air Gap ±8kV IEC 61000-4-2 Contact
- Thermal-Shutdown Protection
- 12-Bump, 1.5mm x 2mm WLP Package
- ♦ -40°C to +85°C Operating Temperature Range

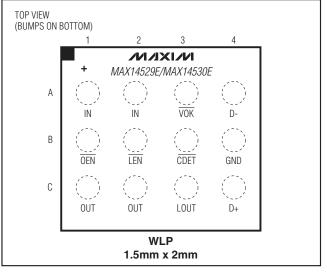
Ordering Information/ Selector Guide

PART	PIN- PACKAGE	TOP MARK	OVLO (V)
MAX14529EEWC+T	12 WLP	AAP	5.75
MAX14530EEWC+T	12 WLP	AAQ	6.8

Note: Both devices are specified over the -40°C to +85°C operating temperature range.

+Denotes a lead(Pb)-free/RoHS-compliant package. T = Tape and reel.

Pin Configuration



For pricing, delivery, and ordering information, please contact Maxim Direct at 1-888-629-4642, or visit Maxim's website at www.maxim-ic.com.

ABSOLUTE MAXIMUM RATINGS

IN to GND	0.3V to +30V
OUT to GND0.3V to mir	h (+12V, IN + 0.3V)
OEN, LEN, VOK, CDET to GND	0.3V to +6V
LOUT to GND	0.3V to +6V
Continuous Current IN to OUT per Ball	1.74A
Continuous Power Dissipation ($T_A = +70^{\circ}C$)	
	7000) 07011/

12-Bump WLP (derate 8.5mW/°C above +70°C).......678mW

Junction-to-Ambient Thermal Resistance (0,	(AL
(Note 1)	118°C/W
Operating Temperature Range	
Junction Temperature	40°C to +150°C
Storage Temperature Range	65°C to +150°C

Lead Temperature (soldering, 10s)+300°C

Note 1: Package thermal resistances were obtained using the method described in JEDEC specification JESD51-7, using a fourlayer board. For detailed information on package thermal considerations, go to <u>www.maxim-ic.com/thermal-tutorial</u>.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

(VIN = 2.2V to 28V, TA = TMIN to TMAX, unless otherwise noted. Typical values are at VIN = +5V, TA = +25°C.) (Note 2)

PARAMETER	SYMBOL	CONDITIONS		MIN	ТҮР	MAX	UNITS
OVERVOLTAGE PROTECTION		·					
Input-Voltage Range	V _{IN}			2.2		28	V
			MAX14529E	5.6	5.75	5.9	
	Vovlo	V _{IN} rising	MAX14530E	6.6	6.8	6.94	- v
Overvoltage Trip Level		Vestalling	MAX14529E	5.4			
		V _{IN} falling	MAX14530E	6.5			
IN Overvoltage Lockout Hysteresis					1		%
		$V_{\overline{\text{OEN}}} = 0$, $V_{\overline{\text{LEN}}} = 5V$, 2.2V < $V_{\text{IN}} < V_{\text{OVLO}}$			95	190	
Supply Current	l _{IN}	$V_{\overline{OEN}} = V_{\overline{LEN}} = 0, 2.2^{\circ}$	$V < V_{IN} < V_{OVLO}$		145	300	μA
		$V_{\overline{\text{OEN}}} = V_{\overline{\text{LEN}}} = 5V, 2.2$	2V < V _{IN} < V _{OVLO}		50	120	
Internal FET R _{ON}	Ron	$I_{LOAD} = 100$ mA, $V_{IN} = 4.5$ V to 5.5V			35	60	mΩ
Maximum Capacitor on OUT	COUTMAX					1000	μF
LOW-DROPOUT REGULATOR							
LDO Output Voltage	VLOUT	$V_{IN} = 5V$		3.219	3.3	3.383	V
LOUT Line Regulation		$V_{IN} = 4.2V$ to 6V			1.65	3.3	mV/V
LOUT Load Regulation		I _{OUT} = 0.1mA to 100mA			0.33	0.66	mV/mA
Current Limit				100		400	mA
Dropout Voltage		I _{OUT} = 50mA (Note 3)			300	500	mV
LOUT Noise		$f = 10$ kHz to 100kHz, $I_{OUT} = 1$ mA			355		μV _{RMS}
CDET FILTER							
Cutoff Frequency	fFILT				0.6		kHz
D- Rising DC Threshold	VTHFILT,R			2.375	2.5	2.625	V
D- Falling DC Threshold	VTHFILT,F				2.35		V
DIGITAL SIGNALS							
Open-Drain Output Low Voltage	VOL	I _{SINK} = 1mA				0.4	V
Open-Drain Leakage Current		$V_{\overline{OEN}} = V_{\overline{LEN}} = 5V$, \overline{VOK} and \overline{CDET} high impedance				1	μA
Input High Voltage	VIH			1.4			V

ELECTRICAL CHARACTERISTICS (continued)

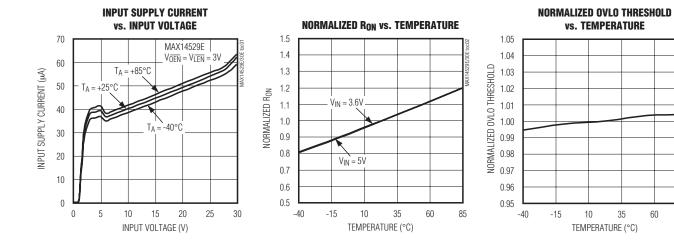
 $(V_{IN} = 2.2V \text{ to } 28V, T_A = T_{MIN} \text{ to } T_{MAX}, \text{ unless otherwise noted. Typical values are at } V_{IN} = 5V, T_A = +25^{\circ}C.)$ (Note 2)

PARAMETER	SYMBOL	CONDITIONS		ТҮР	MAX	UNITS
Input Low Voltage	VIL				0.4	V
Input Leakage Current		$V_{\overline{OEN}} = V_{\overline{LEN}} = 5V$			+1	μΑ
TIMING CHARACTERISTICS	(Figure 1)					
Debounce Time	t INDBC	$2.2V < V_{IN} < V_{OVLO}$ to $V_{OUT} = 10\%$ of V_{IN}		20		ms
Switch Turn-On Time	ton				ms	
Switch Turn-Off Time	tOFF			1.5	3.5	μs
THERMAL PROTECTION						
Thermal Shutdown		Low to high 150			°C	
Thermal Hysteresis		20			°C	
ESD PROTECTION	·					
		Human Body Model		±15		
D+ and D-		IEC 61000-4-2 Air Gap		±15		kV
		IEC 61000-4-2 Contact		±8		

Note 2: Devices are production tested at $T_A = +25^{\circ}$ C. Specifications over temperature limits are guaranteed by design. **Note 3:** Dropout voltage is defined as VOUT - VLOUT when VLOUT is at VLOUT(min).

Typical Operating Characteristics

(T_A = +25°C, unless otherwise noted.)



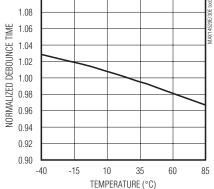
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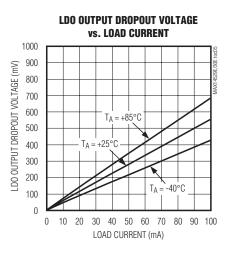
Typical Operating Characteristics (continued)

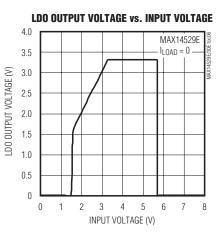
 $(T_A = +25^{\circ}C, unless otherwise noted.)$

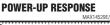
NORMALIZED LDO OUTPUT VOLTAGE vs. OUTPUT CURRENT 1.010 1.005 1.000 1.000 1.000 0.995 0.990 0.990 0.985 0.980 10 20 30 40 50 80 0 60 70 90 100 OUTPUT CURRENT (mA) NORMALIZED DEBOUNCE TIME vs. TEMPERATURE 1.10

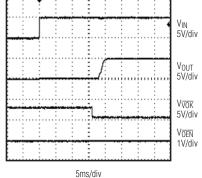
MAX14529E/MAX14530E





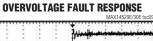


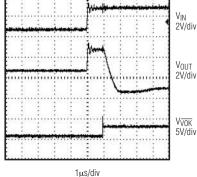




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INPUT CAPACITANCE vs. D+/D- INPUT VOLTAGE 6 5 INPUT CAPACITANCE (pF) 4 3 2 1 0 0 0.5 1.0 1.5 2.0 2.5 3.0 3.5 4.0 4.5 5.5 D+/D- INPUT VOLTAGE (V)

M /X / M



D+/D- INPUT LEAKAGE CURRENT CDET RESPONSE vs. TEMPERATURE 0 10 0.09 INPUT LEAKAGE CURRENT (wa) V_{D+} 2V/div 0.08 0.07 V_{D-} 2V/div 0.06 0.05 0.04 0.03 VCDET 0.02 2V/div 0.01 0 -40 -15 10 35 100µs/div TEMPERATURE (°C)

Pin Description

PIN	NAME	FUNCTION				
PIN	NAME	FUNCTION				
A1, A2	IN	Overvoltage-Protection Input. Bypass IN with a 1μ F ceramic capacitor as close as possible to the device to obtain ± 15 kV HBM ESD protection. No capacitor required to obtain ± 2 kV HBM ESD protection.				
A3	VOK	Voltage Input Good Open-Drain Output. \overline{VOK} is low impedance when \overline{OEN} is driven low after the debounce time is expired (2.2V < V _{IN} < V _{OVLO}).				
A4	D-	SB Data Line with ESD Protection				
B1	OEN	Overvoltage Protection Active-Low Enable Input. Drive OEN high to disconnect OUT from IN.				
B2	LEN	Low-Dropout Active-Low Enable Input.				
B3	CDET	Charger Detection Open-Drain Output. CDET is low if D+ and D- are shorted.				
B4	GND	Ground				
C1, C2	OUT	Overvoltage Switch Output. Bypass OUT with a 0.1μ F ceramic capacitor as close as possible to the device.				
C3	LOUT	Low-Dropout Power Output. Bypass LOUT with a $1\mu\text{F}$ ceramic capacitor as close as possible to the device.				
C4	D+	USB Data Line with ESD Protection				

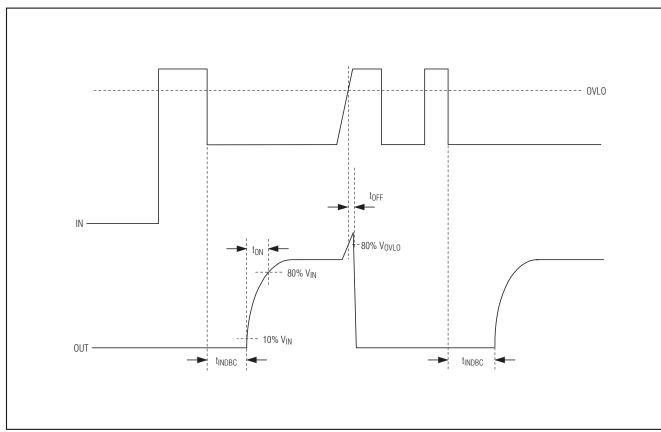
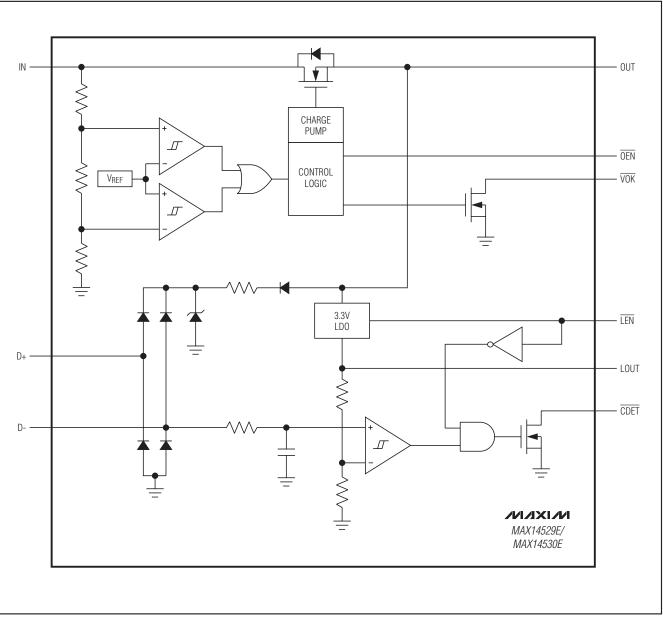


Figure 1. MAX14529E/MAX14530E Timing Diagram

Detailed Description

The MAX14529E/MAX14530E are overvoltage-protection devices with USB charger detection, a low-dropout (LDO) regulator, and ESD protection. These devices feature a low R_{ON} internal FET switch and protect lowvoltage systems against voltage faults up to 28V. When the input voltage exceeds the overvoltage threshold, the internal FET switch is turned off to prevent damage to the protected components. The 20ms debounce time prevents false turn-on of the internal FET switch during startup.

Functional Diagram



Device Operation

The MAX14529E/MAX14530E have an internal oscillator and charge pump that control the turn-on of the internal FET switch. The internal oscillator controls the timers that enable the turn-on of the charge pump and controls the state of the open-drain VOK output. If V_{IN} > V_{OVLO}, the internal oscillator remains off, thus disabling the charge pump. If 2.2V < V_{IN} < V_{OVLO}, the internal charge pump is enabled. The charge-pump turns on the internal FET switch and asserts VOK. At any time, if V_{IN} drops below 2.2V or rises above V_{OVLO}, VOK goes high and the charge pump is disabled, disconnecting OUT from IN.

Overvoltage Lockout (OVLO)

The MAX14529E has a 5.75V (typ) overvoltage threshold (OVLO), while the MAX14530E has a 6.8V (typ) OVLO.

Low Dropout The low-dropout regulator (LOUT) is powered from input voltage and supplies 3.3V (typ) to the USB transceiver. If a lithium-ion (Li+) battery is used to power the USB transceiver, a boost converter is needed. The LDO features a minimum 100mA current capability and low output noise. Drive LEN high to disable the LDO.

Charger Detection

The charger detection detects if there is a short between the USB D+ and D- data lines. If the data lines are shorted together and a dedicated charger is attached, the phone draws more than 500mA to charge the battery; CDET asserts low. If the data lines are not biased properly, then an unidentified device is present and the phone draws no more than 500mA or does not charge at all, depending on its USB compliance level.

Thermal-Shutdown Protection

The MAX14529E/MAX14530E feature thermalshutdown circuitry. The internal switch turns off when the junction temperature exceeds +150°C (typ) and immediately goes into a fault mode. The device exits thermal shutdown after the junction temperature cools by 20°C (typ).

Applications Information

IN Bypass Capacitor

Bypass IN to GND with a 1μ F ceramic capacitor as close as possible to the device for ± 15 kV HBM ESD protection on IN. No capacitor required to obtain ± 2 kV HBM protection. If the power source has significant

inductance due to long lead length, take care to prevent overshoots due to the LC tank circuit and provide protection.

ESD Test Conditions

ESD performance depends on a number of conditions. The MAX14529E/MAX14530E are specified for ± 15 kV HBM typical ESD protection on the D+, D-, and IN pins when IN is bypassed to ground with a 1µF ceramic capacitor.

Human Body Model

Figure 2 shows the Human Body Model, and Figure 3 shows the current waveform it generates when discharged into a low impedance. This model consists of a 100pF capacitor charged to the ESD voltage of interest that is then discharged into the device through a $1.5 \mathrm{k}\Omega$ resistor.

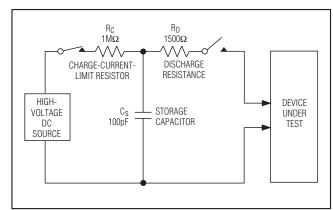


Figure 2. Human Body ESD Test Model

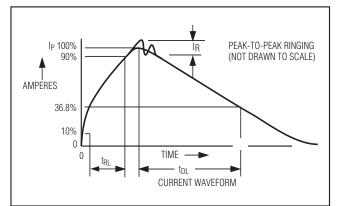


Figure 3. Human Body Current Waveform

MAX14529E/MAX14530E

MAX14529E/MAX14530E

The IEC 61000-4-2 standard covers ESD testing and performance of finished equipment. It does not specifically refer to integrated circuits. The MAX14529E/ MAX14530E are specified for ±15kV Air-Gap Discharge and ±8kV Contact Discharge IEC 61000-4-2 on the D+ and D-pins.

The main difference between tests done using the Human Body Model and IEC 61000-4-2 is higher peak current in IEC 61000-4-2. Because series resistance is

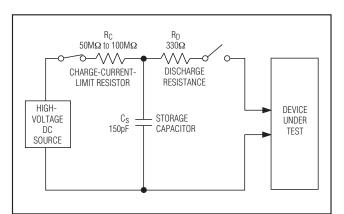


Figure 4. IEC 61000-4-2 ESD Test Model

IEC 61000-4-2

lower in the IEC 61000-4-2 ESD test model (Figure 4), the ESD-withstand voltage measured to this standard is generally lower than that measured using the Human Body Model. Figure 5 shows the current waveform for the ±8kV IEC 61000-4-2 Level 4 ESD Contact Discharge test. The Air-Gap Discharge test involves approaching the device with a charged probe. The Contact Discharge method connects the probe to the device before the probe is energized.

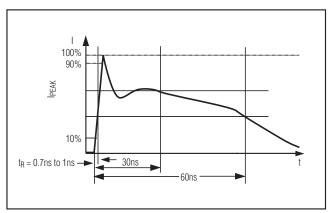


Figure 5. IEC 61000-4-2 ESD Generator Current Waveform

Chip Information

PROCESS: BICMOS

Package Information

For the latest package outline information and land patterns, go to www.maxim-ic.com/packages

PACKAGE TYPE	PACKAGE CODE	DOCUMENT NO.	
12 WLP	W121B2+1	<u>21-0009</u>	

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